Unit: mm

TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (π -MOSVI)

2SK3934

Switching Regulator Applications

Low drain-source ON resistance: RDS (ON) = 0.23Ω (typ.)

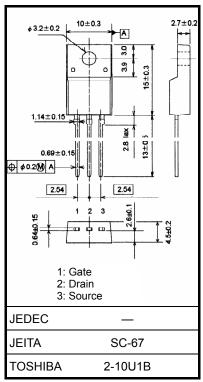
• High forward transfer admittance: $|Y_{fs}| = 8.2 \text{ S (typ.)}$

• Low leakage current: $I_{DSS} = 100 \mu A (V_{DS} = 500 V)$

• Enhancement model: $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

Absolute Maximum Ratings (Ta = 25°C)

Characte	eristic	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage (F	$R_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	500	V	
Gate-source voltage		V _{GSS}	±30	V	
	DC (Note 1)	ID	15		
Drain current	Pulse (t = 1 ms) (Note 1)	I _{DP}	60	Α	
Drain power dissipati	on (Tc = 25°C)	P _D	50	W	
Single pulse avalance	he energy (Note 2)	E _{AS}	1.08	J	
Avalanche current		I _{AR}	15	Α	
Repetitive avalanche	energy (Note 3)	E _{AR}	5.0	mJ	
Channel temperature	•	T _{ch}	150	°C	
Storage temperature	range	T _{stg}	-55~150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

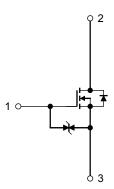
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	2.5	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 8.16mH, $I_{AR} = 15 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.





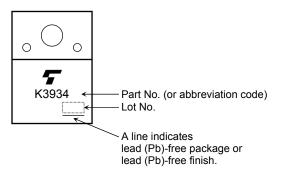
Electrical Characteristics (Ta = 25°C)

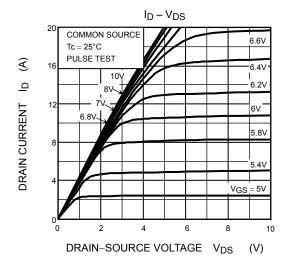
Cha	racteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rent	I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Gate-source brea	akdown voltage	V (BR) GSS	G = ±10 μA, V _{DS} = 0 V ±30 — —		_	V	
Drain cutoff curre	ent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μА
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	500	_	_	V
Gate threshold v	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 7.5 A	_	0.23	0.3	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 7.5 A	2.3	8.2	_	S
Input capacitance	e	C _{iss}		_	3100	_	
Reverse transfer capacitance		C _{rss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	20	_	pF
Output capacitance		C _{oss}		_	270	_	
Switching time	Rise time	t _r	$\begin{array}{c} 10 \text{ V} \\ \text{VGS} \\ 0 \text{ V} \\ \hline \\ 50 \\ \Omega \\ \hline \\ \end{array} \begin{array}{c} \text{I}_D = 7.5 \text{ A} \\ \text{V}_{OUT} \\ \hline \\ \text{V}_{DD} \approx 200 \text{ V} \\ \\ \end{array}$ Duty \leq 1%, $t_W = 10 \mu\text{s}$	_	70	_	
	Turn-on time	t _{on}			130		ns
	Fall time	t _f			70		
	Turn-off time	t _{off}		_	280	_	
Total gate charge		Qg		_	62		
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$	_	40	_	nC
Gate-drain charge		Q _{gd}		_	22	_	

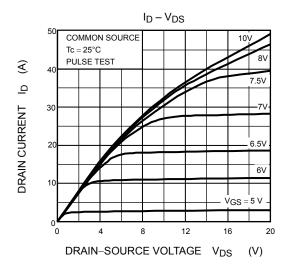
Source-Drain Ratings and Characteristics (Ta = 25°C)

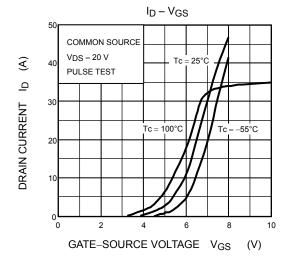
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current	(Note 1)	I _{DR}	_		_	15	Α
Pulse drain reverse current	(Note 1)	I _{DRP}	_	_	_	60	Α
Forward voltage (diode)		V_{DSF}	I _{DR} = 15 A, V _{GS} = 0 V		_	-1.7	V
Reverse recovery time		t _{rr}	$I_{DR} = 15 \text{ A}, V_{GS} = 0 \text{ V},$		1.3	_	μS
Reverse recovery charge		Q _{rr}	dl _{DR} /dt = 100 A/μs	_	18	_	μС

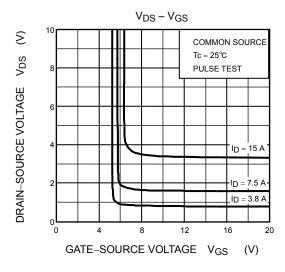
Marking

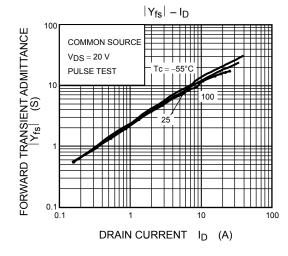


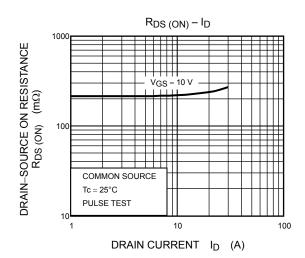


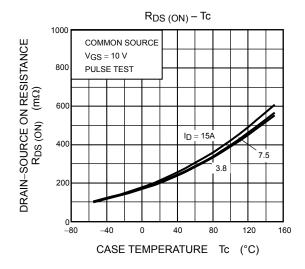


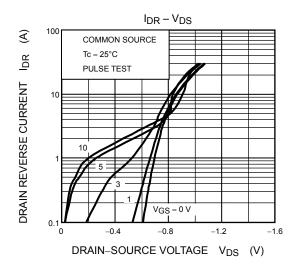


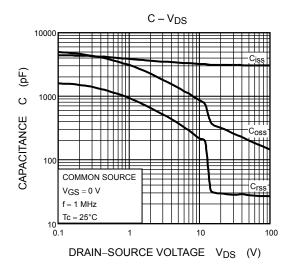


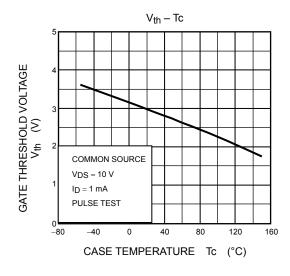


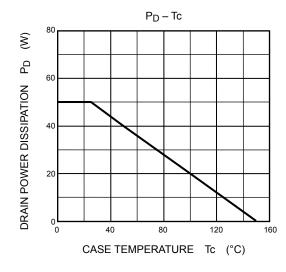


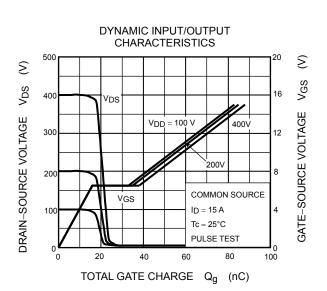


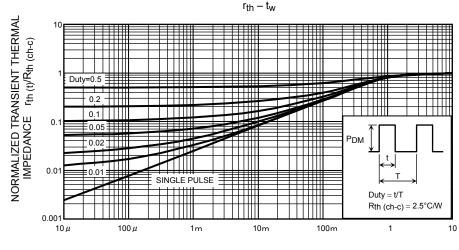




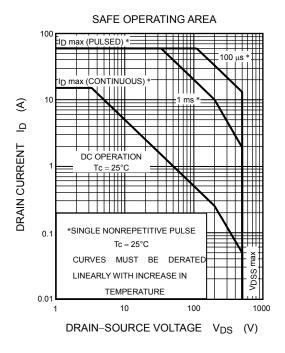


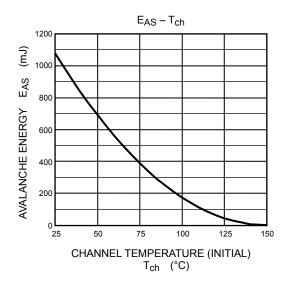


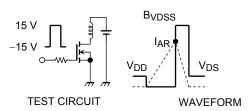




PULSE WIDTH t_w (s)







$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 8.13~mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right)$$

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20070701-EN

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